

PCTEST ENGINEERING LABORATORY, INC.

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HEARING AID COMPATIBILITY

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea Date of Testing: 10/21/2019 - 10/22/2019 Test Site/Location: PCTEST Lab, Columbia, MD, USA Test Report Serial No.: 1M1910220167-01-R1.A3L Date of Issue: 10/29/2019

FCC ID: A3LSMJ737P

APPLICANT: SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: Audio Band Magnetic Testing (T-Coil)

Application Type: Class II Permissive Change

FCC Rule Part(s): CFR §20.19(b)
HAC Standard: ANSI C63.19-2011

285076 D01 HAC Guidance v05

285076 D02 T-Coil testing for CMRS IP v03

DUT Type: Portable Handset

Model: SM-J737P

Test Device Serial No.: Pre-Production Sample [S/N: 34952]

Original Grant Date: 05/07/2018

Class II Permissive Change(s): See FCC Change Document

C63.19-2011 HAC Category: T3 (SIGNAL TO NOISE CATEGORY)

Note: This revised Test Report (S/N: 1M1910220167-01-R1.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This report and category pertain only to the Voice over LTE services supported by this wireless portable device. Please refer to the original certification technical report (S/N: 1M1802160028-12-R1.A3L) for data on other modes supported by this device. This wireless portable device has been shown to be hearing-aid compatible for Voice over LTE services, under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. Test results reported herein relate only to the item(s) tested. North America bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.







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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid in-vitu

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

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2. DUT DESCRIPTION



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Applicant: Samsung Electronics Co., Ltd.

129, Samsung-ro, Maetan dong,

Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea

Model: SM-J737P Serial Number: 34952

HW Version: J737P.02

SW Version: J737PVPU0_0406_PROTOCOL_NV

Antenna: Internal Antenna
DUT Type: Portable Handset

I. LTE Band Selection

This device supports the following pair of LTE bands with similar frequencies: LTE B5 & B26. This pair of LTE bands has the same target power and shares the same transmission path. Since the supported frequency span for the smaller LTE band is completely covered by the larger LTE band, only the larger LTE band (LTE B26) was evaluated for hearing-aid compliance.

Table 2-1A3LSMJ737P HAC Air Interfaces

A3LSMJ737P HAC Air Interfaces						
Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service	Audio Codec Evaluated
	835	VO	No ³	Yes: WIFI or BT	CMRS Voice ¹	FVRC
CDMA	1900	,,,		163. Will 61 51		EVIIC
	EvDO	VD	No ³	Yes: WIFI or BT	Google Duo ²	OPUS
	850	vo	No ³	Yes: WIFL or BT	CMRS Voice ¹	FFR
GSM	1900	***	140	103. 4411 01 21	Cimb voice	LIN .
	GPRS/EDGE	VD	No ³	Yes: WIFI or BT	Google Duo ²	OPUS
	850					
UMTS	1700	VD	No ³	Yes: WIFI or BT	CMRS Voice ¹	NB AMR
UIVITS	1900					
	HSPA	VD	No ³	Yes: WIFI or BT	Google Duo ²	OPUS
	700 (B12)					
	850 (B5)					
LTE (FDD)	850 (B26)	VD	Yes ³	Yes: WIFI or BT	VoLTE ¹ , Google Duo ²	VoLTE: NB AMR, WB AMR Google Duo: OPUS
LIE (FDD)	1700 (B4)	VD	Yes	res: WIFI OF BT	Vol.1E-, Google Duo-	
	1900 (B2)					
	1900 (B25)					
LTE (TDD)	2600 (B41)	VD	Yes ³	Yes: WIFI or BT	VoLTE ¹ , Google Duo ²	VoLTE: NB AMR, WB AMR Google Duo: OPUS
	2450					
	5200 (U-NII 1)					
WIFI	5300 (U-NII 2A)	VD	No ³	Yes: CDMA, GSM, UMTS, or LTE	VoWIFI ² , Google Duo ²	VoWIFI: NB AMR, WB AMR Google Duo: OPUS
	5500 (U-NII 2C)					Google Duo. Or 03
	5800 (U-NII 3)					
BT	2450	DT	No	Yes: CDMA, GSM, UMTS, or LTE	N/A	N/A
ype Transport O = Voice Only IT = Digital Data - Not intended for Voice Services D = CMRS and/or IP Voice over Data Transport This report only pertains to Voice Over UTE services. Please refer to the original certification technical report (\$/N: 1M1802160 12-R1.A3L) for data on other modes supported by this device.						

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3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

I. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be \geq -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per §8.3.2.

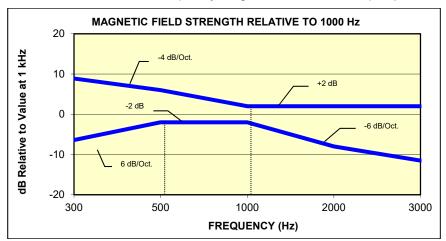


Figure 3-1
Magnetic field frequency response for Wireless Devices with an axial field ≤-15 dB(A/m) at 1 kHz

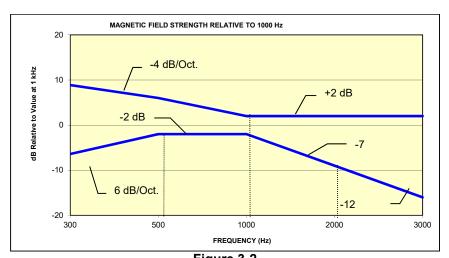


Figure 3-2
Magnetic Field frequency response for wireless devices with an axial field that exceeds
-15 dB(A/m) at 1 kHz

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Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters		
Calegory	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]		
T1	0 to 10 dB		
T2	10 to 20 dB		
Т3	20 to 30 dB		
T4	> 30 dB		
Table 3-1 Magnetic Coupling Parameters			

Note: The FCC limit for SNNR is 20dB and the test data margins will indicate a margin from the FCC limit for compliance.

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4. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

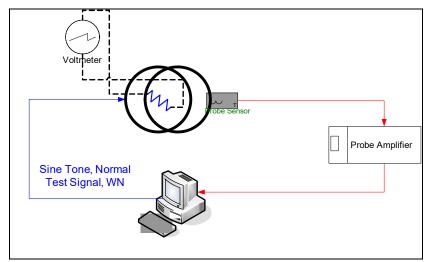


Figure 4-1
Validation Setup with Helmholtz Coil

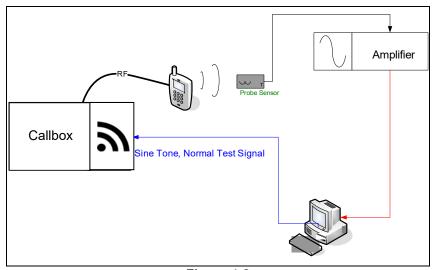


Figure 4-2 T-Coil Test Setup

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II. Scanning Mechanism

Manufacturer: TEM

Accuracy: ± 0.83 cm/meter

Minimum Step Size: 0.1 mm

Maximum speed 6.1 cm/sec

Line Voltage: 115 VAC

Line Frequency: 60 Hz

Material Composite: Delrin (Acetal)

Data Control: Parallel Port

Dynamic Range (X-Y-Z): 45 x 31.75 x 47 cm

Dimensions: 36" x 25" x 38" Operating Area: 36" x 49" x 55"

Reflections: < -20 dB (in anechoic chamber)

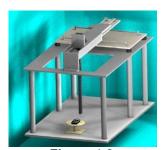


Figure 4-3 RF Near-Field Scanner

III. 3GPP2 Normal Test Signal (Speech)

Manufacturer: 3GPP2 (TIA 1042 §3.3.1)

Modified-IRS weighted, multi-talker speech signal, 4 Male and 4

Stimulus Type: Female speakers (alternating)

Single Sample Duration: 51.62 seconds

Activity Level: 77.4%

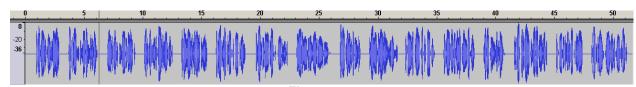


Figure 4-4
Temporal Characteristic of Normal Test Signal

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ABM1 Measurement Block Diagram:



ABM2 Measurement Block Diagram:



Figure 4-5 Magnetic Measurement Processing Steps

IV. Test Procedure

- 1. Ambient Noise Check per C63.19 §7.3.1
 - a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
 - b. "A-weighting" and Half-Band Integration was applied to the measurements.
 - c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is:

- 2. Measurement System Validation (See Figure 4-1)
 - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
 - b. ABM1 Validation

The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_c = \frac{NI}{r\sqrt{1.25^3}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^3}}$$

Where H_c = magnetic field strength in amperes per meter N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.13m; R=10.193Ω and using V=29mV:

$$H_c = \frac{20 \cdot (\frac{0.029}{10.193})}{0.13 \cdot \sqrt{1.25^3}} = 0.316A/m \approx -10dB(A/m)$$

Therefore a pure tone of 1kHz was applied into the coils such that 29mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe

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measurement at -10dB(A/m). This was verified to be within \pm 0.5 dB of the -10dB(A/m) value (see Page 23).

c. Frequency Response Validation

The frequency response through the Helmholtz Coil was verified to be within $0.5~\mathrm{dB}$ relative to 1kHz, between $300-3000~\mathrm{Hz}$ using the Normal signal as shown below:



Figure 4-6 Frequency Response Validation

d. ABM2 Measurement Validation

WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

Table 4-1
ABM2 Frequency Response Validation

	HBI, A -	HBI, A -	
f (Hz)	Measured	Theoretical	dB Var.
	(dB re 1kHz)	(dB re 1kHz)	
100	-16.180	-16.170	-0.010
125	-13.257	-13.250	-0.007
160	-10.347	-10.340	-0.007
200	-8.017	-8.010	-0.007
250	-5.925	-5.920	-0.005
315	-4.045	-4.040	-0.005
400	-2.405	-2.400	-0.005
500	-1.212	-1.210	-0.002
630	-0.349	-0.350	0.001
800	0.071	0.070	0.001
1000	0.000	0.000	0.000
1250	-0.503	-0.500	-0.003
1600	-1.513	-1.510	-0.003
2000	-2.778	-2.780	0.002
2500	-4.316	-4.320	0.004
3150	-6.166	-6.170	0.004
4000	-8.322	-8.330	0.008
5000	-10.573	-10.590	0.017
6300	-13.178	-13.200	0.022
8000	-16.241	-16.270	0.029
10000	-19.495	-19.520	0.025

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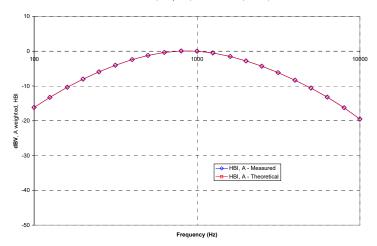
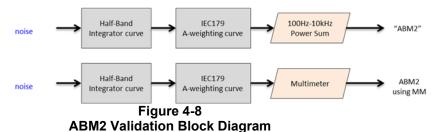


Figure 4-7
ABM2 Frequency Response Validation

The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and A-weighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-8). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:



The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 4-2
ABM2 Power Sum Validation

WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)
-60	-60.36	-60.2	0.16
-50	-50.19	-50.13	0.06
-40	-40.14	-40.03	0.11
-30	-30.13	-30.01	0.12
-20	-20.12	-20	0.12
-10	-10.14	-10	0.14

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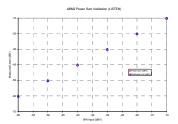
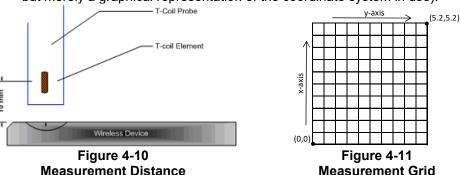


Figure 4-9
ABM2 Power Sum Validation

- 3. Measurement Test Setup
 - a. Fine scan above the WD (TEM)
 - i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-11, the grid is not to scale but merely a graphical representation of the coordinate system in use):



- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-13 after a T-coil orientation was fully measured with the SoundCheck system.
- b. Speech Signal Setup to Base Station Simulator
 - See Section 5 for more information regarding CMW500 audio level settings for Voice Over LTE (VoLTE).
- c. Real-Time Analyzer (RTA)
 - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- d. WD Radio Configuration Selection
 - i. The device was chosen to be tested in the worst-case ABM2 condition (LTE configuration information can be found in Section 5.)
- 4. Signal Quality Data Analysis
 - a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
 - b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the

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length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.

- ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-6. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
- iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.

c. Signal Quality Index

- i. Ensuring the WD was at maximum RF power, maximum volume, backlight off, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
- ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
- This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

V. Test Setup

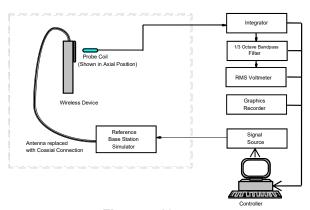


Figure 4-12 Audio Magnetic Field Test Setup

Environmental conditions such as temperature and relative humidity are monitored to ensure there are no impacts on system specifications. Proper voltage and power line frequency conditions are maintained with three phase power sources. Environmental noise and reflections are monitored through system checks.

VI. Deviation from C63.19 Test Procedure

Non-conducted RF connection due to inaccessible RF ports.

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REV 3.3.M

VII. Air Interface Technologies Tested

All air interfaces which support voice capabilities over a managed CMRS or pre-installed OTT VoIP applications were tested for T-coil unless otherwise noted. See Table 2-1 for more details regarding which modes were tested.

VIII. Wireless Device Channels and Frequencies

1. 4G (LTE) Modes

The middle channel for every band and bandwidth combination was tested for each probe orientation. The band and bandwidth combination from each probe orientation resulting in the worst-case SNNR was additionally tested using low and high channels for that band and bandwidth combination. Low-mid and mid-high channels are additionally tested for LTE TDD. See Tables 6-2 to 6-8 for LTE bandwidths and channels.

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IX. Test Flow

The flow diagram below was followed (From C63.19):

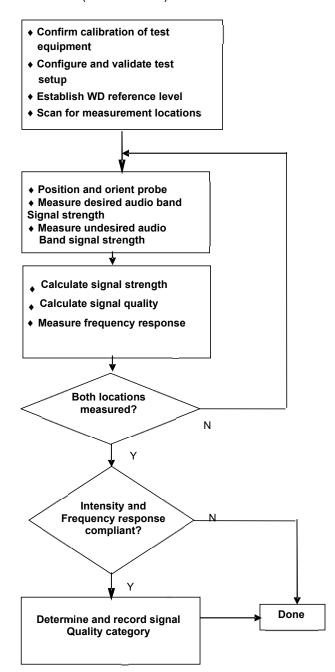


Figure 4-13 C63.19 T-Coil Signal Test Process

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5. VOLTE TEST SYSTEM SETUP AND DUT CONFIGURATION

I. Test System Setup for VoLTE over IMS T-coil Testing

1. Equipment Setup

The general test setup used for VoLTE over IMS is shown below. The callbox used when performing VoLTE over IMS T-coil measurements is a CMW500. The Data Application Unit (DAU) of the CMW500 was used to simulate the IP Multimedia Subsystem (IMS) server.

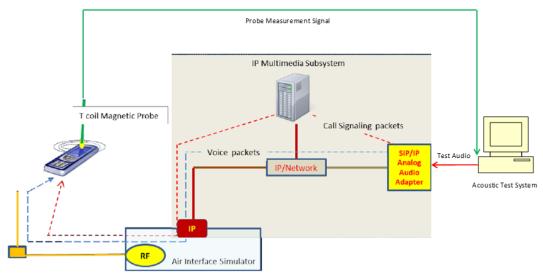


Figure 5-1
Test Setup for VoLTE over IMS T-Coil Measurements

2. Audio Level Settings

According to the July 2012 interpretations by the C63 Committee regarding the appropriate audio levels to be used for VoLTE over IMS T-coil testing, -16dBm0 shall be used for the normal speech input level*. The CMW500 base station simulator was manually configured to ensure that the settings for speech input and full scale levels resulted in the -16dBm0 speech input level to the DUT for the VoLTE over IMS connection.

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^{*} http://c63.org/documents/misc/posting/new_interpretations.htm

II. DUT Configuration for VoLTE over IMS T-coil Testing

1. Radio Configuration

An investigation was performed to determine the modulation and RB configuration to be used for testing. The effects of modulation and RB configuration were found to be independent of band and bandwidth; therefore, only one band and bandwidth were used for this investigation. 16QAM, 1RB, 0RB offset was used for the testing as the worst-case configuration for the handset. See below table for SNNR comparison between different radio configurations:

Table 5-1
VoLTE over IMS SNNR by Radio Configuration

				0.11.11.	,				
Band	Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
25	1882.5	26365	20	QPSK	1	0	6.69	-41.71	48.40
25	1882.5	26365	20	QPSK	1	50	6.60	-41.57	48.17
25	1882.5	26365	20	QPSK	1	99	6.73	-41.35	48.08
25	1882.5	26365	20	QPSK	50	0	6.42	-41.70	48.12
25	1882.5	26365	20	QPSK	50	25	6.68	-41.61	48.29
25	1882.5	26365	20	QPSK	50	50	6.61	-41.60	48.21
25	1882.5	26365	20	QPSK	100	0	6.58	-41.64	48.22
25	1882.5	26365	20	16QAM	1	0	6.59	-41.36	47.95
25	1882.5	26365	20	16QAM	1	50	6.63	-41.46	48.09
25	1882.5	26365	20	16QAM	1	99	6.38	-41.64	48.02
25	1882.5	26365	20	16QAM	50	0	6.56	-41.69	48.25
25	1882.5	26365	20	16QAM	50	25	6.63	-41.68	48.31
25	1882.5	26365	20	16QAM	50	50	6.62	-41.78	48.40
25	1882.5	26365	20	16QAM	100	0	6.62	-41.70	48.32

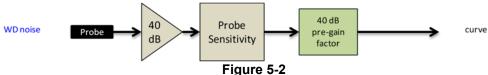
2. Codec Configuration

An investigation was performed to determine the audio codec configuration to be used for testing. The effects of codec configuration were found to be independent of band and bandwidth; therefore, only one band and bandwidth were used for this investigation. The WB AMR 6.60kbps setting was used for the audio codec on the CMW500 for VoLTE over IMS T-coil testing. See below table for comparisons between different codecs and codec data rates:

Table 5-2
AMR Codec Investigation – VoLTE over IMS

7 mint obdob introdugation vol. 12 ovol into							
Codec Setting:	WB AMR 23.85kbps	WB AMR 6.60kbps	NB AMR 12.2kbps	NB AMR 4.75kbps	Orientation	Band / BW	Channel
ABM1 (dBA/m)	6.72	6.43	10.30	9.98			
ABM2 (dBA/m)	-41.39	-41.31	-41.35	-41.38	- Axial	Band 25 20MHz	26365
Frequency Response	Pass	Pass	Pass	Pass			
S+N/N (dB)	48.11	47.74	51.65	51.36			

- Mute on; Backlight off; Max Volume; Max Contrast
- TPC = "Max Power"



Audio Band Magnetic Curve Measurement Block Diagram

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3. LTE TDD Uplink-Downlink Configuration Investigation for VoLTE over IMS

An investigation was performed to determine the worst-case Uplink-Downlink configuration for VoLTE over IMS T-Coil testing.

Per 3GPP TS 36.211, the total frame length for each TDD radio frame of length T_f = 307200 \cdot T_s = 10 ms, where T_s is a number of time units equal to 1/(15000 x 2048) seconds. Additionally, each radio frame consists of 10 subframes, each of length 30720 \cdot T_s = 1 ms, and subframes can be designated as uplink (U), downlink (D), or special subframe (S), depending on the Uplink-Downlink configuration as indicated in Table 4.2-2 of 3GPP TS 36.211. In the transmission duty factor calculation, the special subframe configuration with the shortest UpPTS duration within the special subframe is used and will be applied for measurement. From 3GPP TS 36.211 Table 4.2-1, the shortest UpPTS is 2192 \cdot Ts which occurs in the normal cyclic prefix and special subframe configuration 4.

See table below outlining the calculated transmission duty cycles for each Uplink-Downlink configuration:

Table 5-3
Uplink-Downlink Configurations for Type 2 Frame Structures

	opinik bowinink configurations for Typo 2 Framo otractareo											
Uplink-downlink	Downlink-to-Uplink				Su	bframe	e numb	er				Calculated Transmission
configuration	Switch-point periodicity	0	1	2	3	4	5	6	7	8	9	Duty Cycle (%)
0	5 ms	D	S	U	U	U	D	S	J	U	U	61.4%
1	5 ms	D	S	U	U	D	D	S	J	U	D	41.4%
2	5 ms	D	S	U	D	D	D	S	J	D	D	21.4%
3	10 ms	D	S	U	U	U	D	D	D	D	D	30.7%
4	10 ms	D	S	U	U	D	D	D	D	D	D	20.7%
5	10 ms	D	S	U	D	D	D	D	D	D	D	10.7%
6	5 ms	D	S	U	U	U	D	S	U	U	D	51.4%

a. Power Class 3 Uplink-Downlink Configuration Investigation

Power class 3 was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 3, all configurations (0-6) are supported. The configuration which resulted in the worst SNNR was used for full testing. Uplink-Downlink configuration 1 was used as the worst-case configuration for Power Class 3 VoLTE over IMS T-Coil testing. See table below for the SNNR comparison between each Uplink-Downlink configuration:

Table 5-4
Power Class 3 VoLTE over IMS SNNR by UL-DL Configuration

Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	UL-DL Configuration	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
2593.0	40620	20	16QAM	1	0	0	6.95	-41.15	48.10
2593.0	40620	20	16QAM	1	0	1	6.59	-41.26	47.85
2593.0	40620	20	16QAM	1	0	2	6.77	-41.31	48.08
2593.0	40620	20	16QAM	1	0	3	6.72	-41.40	48.12
2593.0	40620	20	16QAM	1	0	4	6.79	-41.45	48.24
2593.0	40620	20	16QAM	1	0	5	6.73	-41.31	48.04
2593.0	40620	20	16QAM	1	0	6	7.05	-41.11	48.16

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b. Power Class 2 Uplink-Downlink Configuration Investigation

Power Class 2 was evaluated with the following radio configuration: channel 40620, 20MHz BW, 16QAM, 1RB, 0RB Offset. For Power Class 2, configurations 1-5 are supported. The configuration which resulted in the worst SNNR was used for full testing. Uplink-Downlink configuration 1 was used as the worst-case configuration for Power Class 2 VoLTE over IMS T-Coil testing. See table below for the SNNR comparison between each Uplink-Downlink configuration:

Table 5-5
Power Class 2 VoLTE over IMS SNNR by UL-DL Configuration

						,			
Frequency [MHz]	Channel	Bandwidth [MHz]	Modulation	RB Size	RB Offset	UL-DL Configuration	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	SNNR [dB]
2593.0	40620	20	16QAM	1	0	1	6.58	-40.44	47.02
2593.0	40620	20	16QAM	1	0	2	6.99	-40.68	47.67
2593.0	40620	20	16QAM	1	0	3	6.93	-40.56	47.49
2593.0	40620	20	16QAM	1	0	4	6.54	-40.86	47.40
2593.0	40620	20	16QAM	1	0	5	6.52	-41.05	47.57

Note: LTE TDD B41 Power Class 2 only supports UL-DL configurations 1-5, not 0 or 6.

c. Conclusion

Per the investigations above, UL-DL Configuration 1 was used to evaluate both Power Class 3 & Power Class 2 VoLTE over IMS.

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6. T-COIL TEST SUMMARY

Table 6-1
Consolidated Tabled Results

		-	esponse rgin	_	netic / Verdict		SNNR dict	Margin from FCC Limit	C63.19-2011
C63.40	9 Section	8.3	3.2	8.3	3.1	8.3	3.4	(dB)	Rating
C63. 18	9 Section	Axial	Radial	Axial	Radial	Axial	Radial		
	B12	PASS	NA	PASS	PASS	PASS	PASS		
	B26	PASS	NA	PASS	PASS	PASS	PASS		
LTE FDD	B4	PASS	NA	PASS	PASS	PASS	PASS	-16.10	T4
	B2	PASS	NA	PASS	PASS	PASS	PASS		
	B25	PASS	NA	PASS	PASS	PASS	PASS		
LTE TOD	B41 (PC3)	PASS	NA	PASS	PASS	PASS	PASS	E 60	Тэ
LTE TDD	B41 (PC2)	PASS	NA	PASS	PASS	PASS	PASS	-5.62	Т3

I. Raw Handset Data

Table 6-2 Raw Data Results for LTE B12

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		10MHz	23095	6.22	-41.26		1.15	47.48	20.00	-27.48	T4	
		5MHz	23095	6.84	-40.88		1.12	47.72	20.00	-27.72	T4	
	Avial	3MHz	23095	6.04	-41.17	-58.57	1.32	47.21	20.00	-27.21	T4	2.6, 2.6
Axial	1.4MHz	23173	6.45	-41.35	-50.57	1.16	47.80	20.00	-27.80	T4	2.0, 2.0	
		1.4MHz	23095	6.14	-40.97		1.20	47.11	20.00	-27.11	T4	l
		1.4MHz	23017	6.35	-41.16		1.26	47.51	20.00	-27.51	T4	
LIE Ballu 12		10MHz	23095	-3.20	-40.86			37.66	20.00	-17.66	T4	
		5MHz	23095	-3.26	-40.08			36.82	20.00	-16.82	T4	
	Radial	3MHz	23095	-3.20	-40.10	-60.56	N/A	36.90	20.00	-16.90	T4	2.6, 1.8
	Naulai	1.4MHz	23173	-3.37	-41.65	-00.56	IVA	38.28	20.00	-18.28	T4	2.0, 1.0
		1.4MHz	23095	-3.28	-39.82	-	1	36.54	20.00	-16.54	T4	
		1.4MHz	23017	-3.29	-39.39			36.10	20.00	-16.10	T4	

Table 6-3 Raw Data Results for LTE B26

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		15MHz	26865	6.78	-41.01		1.25	47.79	20.00	-27.79	T4	
		10MHz	26865	6.45	-41.28		1.19	47.73	20.00	-27.73	T4	
	Axial	5MHz	26865	6.49	-41.40	-58.57	1.14	47.89	20.00	-27.89	T4	2.6, 2.6
		3MHz	26865	6.25	-41.41		1.25	47.66	20.00	-27.66	T4	
LTE Band 26		1.4MHz	26865	6.08	-41.40		1.24	47.48	20.00	-27.48	T4	
LIE Banu 20		15MHz	26865	-3.13	-40.58			37.45	20.00	-17.45	T4	
		10MHz	26865	-3.39	-40.63	-60.56 N/A		37.24	20.00	-17.24	T4	
	Radial	5MHz	26865	-3.25	-40.92		-60.56 N/A	37.67	20.00	-17.67	T4	2.6 1.8
		3MHz	26865	-3.31	-41.74			38.43	20.00	-18.43	T4	
		1.4MHz	26865	-3.15	-42.24			39.09	20.00	-19.09	T4	

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Table 6-4 Raw Data Results for LTE B4

					Dutait							
Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		20MHz	20175	6.45	-41.37		1.24	47.82	20.00	-27.82	T4	
		15MHz	20175	6.49	-41.43		1.27	47.92	20.00	-27.92	T4	
Axial	10MHz	20175	6.65	-41.35	-58.57	1.18	48.00	20.00	-28.00	T4	2.6, 2.6	
	5MHz	20175	6.38	-41.23	-56.57	1.21	47.61	20.00	-27.61	T4	2.6, 2.6	
		3MHz	20175	6.25	-41.26		1.21	47.51	20.00	-27.51	T4	
LTE Band 4		1.4MHz	20175	6.46	-41.26		1.21	47.72	20.00	-27.72	T4	
LIE Danu 4		20MHz	20175	-3.17	-42.49			39.32	20.00	-19.32	T4	
		15MHz	20175	-3.42	-42.67			39.25	20.00	-19.25	T4	
	Radial	10MHz	20175	-3.27	-41.79	-60.56	N/A	38.52	20.00	-18.52	T4	2.6 1.8
	Naulai	5MHz	20175	-3.14	-40.89	-00.56	IVA	37.75	20.00	-17.75	T4	2.0 1.0
		3MHz	20175	-3.19	-40.64	7 I	1 -	37.45	20.00	-17.45	T4	
		1.4MHz	20175	-3.18	-40.18	1		37.00	20.00	-17.00	T4	

Table 6-5 Raw Data Results for LTE B25

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		20MHz	26365	6.68	-41.11		1.16	47.79	20.00	-27.79	T4	
		15MHz	26365	6.69	-41.26		1.31	47.95	20.00	-27.95	T4	
	Avial	10MHz	26365	6.38	-41.31	-58.57	1.24	47.69	20.00	-27.69	T4	2.6, 2.6
Axial	5MHz	26365	6.43	-41.28	-56.57	1.30	47.71	20.00	-27.71	T4	2.6, 2.6	
		3MHz	26365	6.54	-41.23		1.19	47.77	20.00	-27.77	T4	
		1.4MHz	26365	6.67	-41.31		1.20	47.98	20.00	-27.98	T4	
LIE Ballu 25		20MHz	26365	-3.19	-40.36			37.17	20.00	-17.17	T4	
		15MHz	26365	-3.55	-40.68			37.13	20.00	-17.13	T4	
	Dadial	10MHz	26365	-3.13	-41.50	-60.56	N/A	38.37	20.00	-18.37	T4	2.6 1.8
	Radial	5MHz	26365	-3.13	-41.32	-00.56	IWA	38.19	20.00	-18.19	T4	2.0 1.8
		3MHz	26365	-3.10	-41.31			38.21	20.00	-18.21	T4	
		1.4MHz	26365	-3.05	-41.00			37.95	20.00	-17.95	T4	

Table 6-6 Raw Data Results for LTE B2

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates	
		20MHz	18900	6.64	-41.25		1.25	47.89	20.00	-27.89	T4		
		15MHz	18900	6.61	-41.23		1.25	47.84	20.00	-27.84	T4		
	Axial	10MHz	18900	6.75	-41.19	-58.57	1.29	47.94	20.00	-27.94	T4	2.6, 2.6	
Axiai	5MHz	18900	6.18	-41.26	-58.57	1.23	47.44	20.00	-27.44	T4	2.0, 2.0		
	3MHz	18900	6.41	-41.16		1.23	47.57	20.00	-27.57	T4			
LTE Band 2	TE Pand 2	1.4MHz	18900	6.66	-41.21		1.23	47.87	20.00	-27.87	T4		
LIE Banu 2		20MHz	18900	-3.18	-40.60				37.42	20.00	-17.42	T4	
		15MHz	18900	-3.00	-39.92			36.92	20.00	-16.92	T4		
	Dodial	10MHz	18900	-3.19	-40.43	-60.56	N/A	37.24	20.00	-17.24	T4	2.6 1.8	
	Radial	5MHz	18900	-3.29	-40.18	-60.56	IVA	36.89	20.00	-16.89	T4	2.0 1.0	
		3MHz	18900	-3.49	-40.11			36.62	20.00	-16.62	T4		
		1.4MHz	18900	-3.31	-40.50			37.19	20.00	-17.19	T4		

Table 6-7 Raw Data Results for LTE B41 Power Class 3

	Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
Ī			20MHz	40620	6.80	-41.27	-58.57	1.18	48.07	20.00	-28.07	T4	
		Axial	15MHz	40620	6.68	-41.23		1.20	47.91	20.00	-27.91	T4	2.6, 2.6
		Axidi	10MHz	40620	6.91	-41.24		1.14	48.15	20.00	-28.15	T4	2.0, 2.0
	TE Band 41	TE Band 44	5MHz	40620	6.96	-41.29		1.21	48.25	20.00	-28.25	T4	
ľ	LIE Band 41		20MHz	40620	-3.32	-35.28			31.96	20.00	-11.96	T4	
		Radial	15MHz	40620	-3.18	-35.11	-60.56	N/A	31.93	20.00	-11.93	T4	2.6. 1.8
		Radiai	10MHz	40620	-3.44	-35.27	-00.56	-60.56 N/A	31.83	20.00	-11.83	T4	2.0, 1.0
			5MHz	40620	-3.15	-34.96			31.81	20.00	-11.81	T4	

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Table 6-8
Raw Data Results for LTE B41 Power Class 2

Mode	Orientation	Bandwidth	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		20MHz	40620	6.86	-40.42	-40.42 -40.33 -40.02 -40.47 -40.24 -40.30 -40.21 -40.48	1.17	47.28	20.00	-27.28	T4	
		15MHz	40620	6.64	-40.33		1.18	46.97	20.00	-26.97	T4	
		10MHz	41490	6.67	-40.02		1.26	46.69	20.00	-26.69	T4	2.6, 2.6
	Axial	10MHz	41055	6.93	-40.47		1.30	47.40	20.00	-27.40	T4	
	Axiai	10MHz	40620	6.72	-40.24		1.21	46.96	20.00	-26.96	T4	
		10MHz	40185	6.65	-40.30		1.20	46.95	20.00	-26.95	T4	
	TE Bond 44	10MHz	39750	6.95	-40.21		1.36	47.16	20.00	-27.16	T4	
LTE Band 41		5MHz	40620	6.63	-40.48		1.15	47.11	20.00	-27.11	T4	
LIE Ballu 41		20MHz	40620	-3.19	-29.88			26.69	20.00	-6.69	Т3	
		15MHz	40620	-3.42	-30.33		26.91	20.00	-6.91	Т3		
		10MHz	41490	-3.25	-28.87			25.62	20.00	-5.62	Т3	
	Radial	10MHz	41055	-3.12	-29.52	60.56	N/A	26.40	20.00	-6.40	Т3	2.6, 1.8
	Naulai	10MHz	40620	-3.21	-29.58	30.76	IWA	26.37	20.00	-6.37	Т3	2.0, 1.0
		10MHz	40185	-3.11	-30.76			27.65	20.00	-7.65	Т3	
		10MHz	39750	-3.40	-29.21			25.81	20.00	-5.81	Т3	
		5MHz	40620	-3.39	-30.87			27.48	20.00	-7.48	Т3	

II. Test Notes

A. General

- 1. Phone Condition: Mute on; Backlight off; Max Volume; Max Contrast
- 2. 'Radial' orientation refers to radial transverse.
- Hearing Aid Mode (Phone→Call Settings→More Settings→Hearing aids) was set to ON for Frequency Response compliance
- 4. Speech Signal: 3GPP2 Normal Test Signal
- 5. Bluetooth and WIFI were disabled while testing 4G modes.
- 6. The Margin from FCC limit column indicates a margin from the FCC limit for compliance (T3).

B. LTE FDD

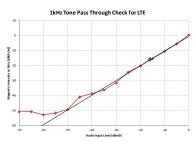
- 1. Power Configuration: TPC = "Max Power"
- 2. Radio Configuration: 16QAM, 1RB, 0RB offset
- 3. Vocoder Configuration: WB AMR 6.60kbps
- 4. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low and high channels for those combinations. LTE Band 12 at 1.4MHz is the worst-case for both the Axial and Radial probe orientations.

C. LTE TDD

- 1. Power Configuration: TPC = "Max Power"
- 2. Radio Configuration: 16QAM, 1RB, 0RB offset
- 3. Power Class 3 Uplink-Downlink configuration: 1
- 4. Power Class 2 Uplink-Downlink configuration: 1
- 5. Vocoder Configuration: WB AMR 6.60kbps
- 6. The worst-case band and bandwidth combination for each probe orientation is additionally tested on the low, low-mid, high-mid, and high channels for those combinations. LTE Band 41 (Powers Class 2) at 10MHz is the worst-case for both the Axial and Radial probe orientations.

FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 22 of 46
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III. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -16 dBm0 for VoLTE over IMS. This measurement was taken in the axial configuration above the maximum location.

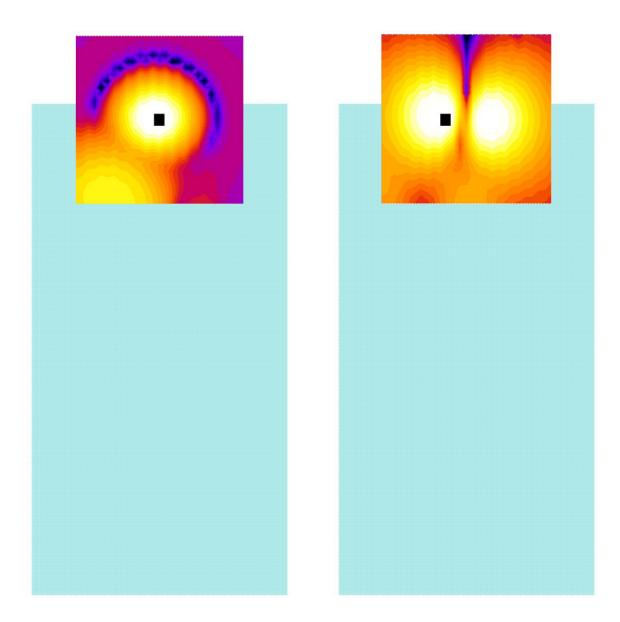
IV. T-Coil Validation Test Results

Table 6-9
Helmholtz Coil Validation Table of Results

ltem	Target	Result	Verdict
Axial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-9.895	PASS
Environmental Noise	< -58 dBA/m	-58.57	PASS
Frequency Response, from limits	> 0 dB	0.50	PASS
Radial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-10.177	PASS
Environmental Noise	< -58 dBA/m	-60.56	PASS
Frequency Response, from limits	> 0 dB	0.70	PASS

FCC ID: A3LSMJ737P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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V. ABM1 Magnetic Field Distribution Scan Overlays



Axial Radial (Transverse)

Figure 6-1 T-Coil Scan Overlay Magnetic Field Distributions

Notes:

- 1. Final measurement locations are indicated by a cursor on the contour plots.
- 2. See Test Setup Photographs for actual WD overlay.

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REV 3.3.M 08/13/2019

7. MEASUREMENT UNCERTAINTY

Table 7-1 Uncertainty Estimation Table

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)	
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	` ,	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%		
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%		
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%		
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%		
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%		
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%		
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%		
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%		
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%		
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%		
Combined standard uncertainty	Combined standard uncertainty, uc (k=1) 17.7% 0.71							
Expanded uncertainty (k=2),	Expanded uncertainty (k=2), 95% confidence level							

Notes:

- 1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.
- All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Daga OF of 46
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8. EQUIPMENT LIST

Table 8-1 Equipment List

	Equipment List								
Manufacturer Model		Description	Cal Date	Cal Interval	Cal Due	Serial Number			
Control Company	4040	Temperature / Humidity Monitor	2/28/2018	Biennial	2/28/2020	150761911			
Dell	Latitude E6540	SoundCheck Acoustic Analyzer Laptop	9/6/2018	Biennial	9/6/2020	2655082910			
Listen	SoundConnect	Microphone Power Supply	9/6/2018	Biennial	9/6/2020	0899-PS150			
RME	Fireface UC	Soundcheck Acoustic Analyzer External Audio Interface	9/6/2018	Biennial	9/6/2020	23792992			
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	1/30/2019	Annual	1/30/2020	162125			
Seekonk	NC-100	Torque Wrench (8" lb)	5/10/2018	Biennial	5/10/2020	21053			
TEM	Axial T-Coil Probe	Axial T-Coil Probe	9/19/2018	Biennial	9/19/2020	TEM-1123			
TEM	Radial T-Coil Probe	Radial T-Coil Probe	9/19/2018	Biennial	9/19/2020	TEM-1129			
TEM	Helmholtz Coil	Helmholtz Coil	10/10/2018	Biennial	10/10/2020	SBI 1052			
TEM		HAC System Controller with Software	N/A		N/A	N/A			
TEM		HAC Positioner	N/A		N/A	N/A			

FCC ID: A3LSMJ737P	PCTEST	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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9. TEST DATA

FCC ID: A3LSMJ737P		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 27 of 46
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PCTEST Hearing-Aid Compatibility Facility

DUT: HH Coil - SN: SBI 1052

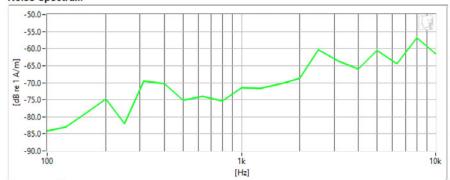
Type: HH Coil Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

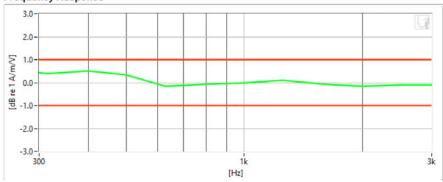
Equipment:

- Probe: Axial T-Coil Probe SN: TEM-1123; Calibrated: 09/19/2018
- Helmholtz Coil SN: SBI 1052; Calibrated: 10/10/2018

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-9.895 dB	\checkmark	Max/Min	-9.5/-10.5
Verification ABM2	-58.57 dB	•	Maximum	-58.0
Frequency Response Margin	500m dB	\checkmark	Tolerance curves	Aligned Data

FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 28 of 46
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or Eor ricaring Aid Companionity racin

DUT: HH Coil – SN: SBI 1052

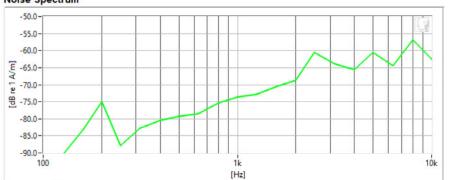
Type: HH Coil
Serial: SBI 1052

Measurement Standard: ANSI C63.19-2011

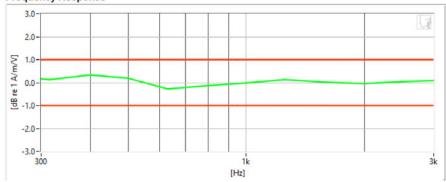
Equipment:

- Probe: Radial T-Coil Probe SN: TEM-1129; Calibrated: 09/19/2018
- Helmholtz Coil SN: SBI 1052; Calibrated: 10/10/2018

Noise Spectrum



Frequency Response



Results

Verification 1kHz Intensity	-10.177	dB	\checkmark	Max/Min	-9.5/-10.5
Verification ABM2	-60.56	dB	•	Maximum	-58.0
Frequency Response Margin	700m	dB	•	Tolerance curves	Aligned Data

FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 29 of 46
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Type: Portable Handset Serial: 34952

Measurement Standard: ANSI C63.19-2011

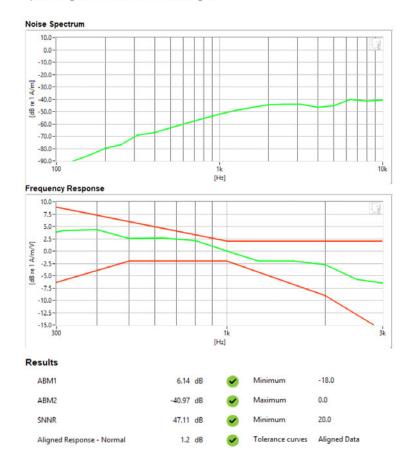
Equipment:

Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 09/19/2018

Test Configuration:

Mode: LTE FDD Band 12Bandwidth: 1.4MHzChannel: 23095

· Speech Signal: 3GPP2 Normal Test Signal



FCC ID: A3LSMJ737P	PCTEST	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dogo 20 of 46
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Type: Portable Handset Serial: 34952

Measurement Standard: ANSI C63.19-2011

Equipment:

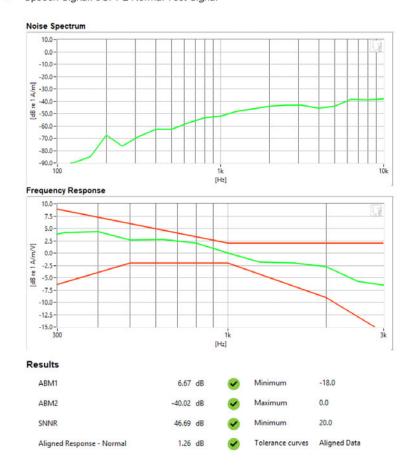
Probe: Axial T-Coil Probe – SN: TEM-1123; Calibrated: 09/19/2018

Test Configuration:

Mode: LTE TDD Band 41 (PC2)

Bandwidth: 10MHzChannel: 41490

· Speech Signal: 3GPP2 Normal Test Signal



FCC ID: A3LSMJ737P	PCTEST	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 31 of 46
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Type: Portable Handset Serial: 34952

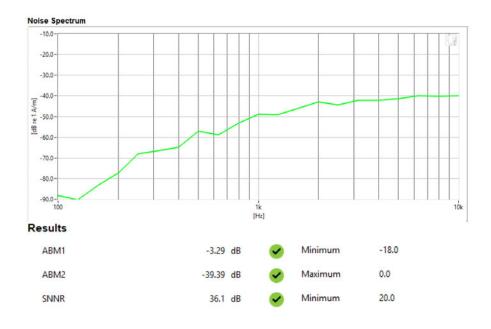
Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 09/19/2018

Test Configuration:

Mode: LTE FDD Band 12Bandwidth: 1.4MHzChannel: 23017



FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dog 22 of 46
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Type: Portable Handset Serial: 34952

Measurement Standard: ANSI C63.19-2011

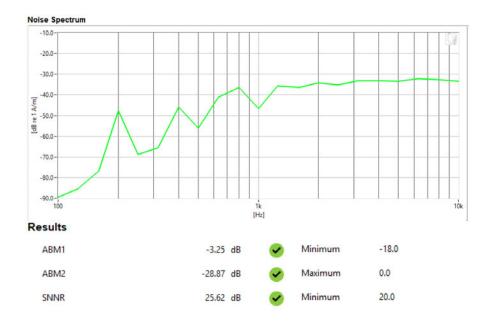
Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1129; Calibrated: 09/19/2018

Test Configuration:

Mode: LTE TDD Band 41 (PC2)

Bandwidth: 10MHzChannel: 41490



FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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10. CALIBRATION CERTIFICATES

FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Dog 24 of 46
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Certificate of Calibration

for

AXIAL T COIL PROBE

Manufactured by:

TEM CONSULTING LP

Model No:

AXIAL T COIL PROBE

Serial No: Calibration Recall No: TEM-1123 29156

Submitted By:

Customer:

Andrew Harwell

Company:

PCTest Engineering Lab

Address:

6660-B Dobbin Road

Columbia

MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No.

AXIAL T C TEM C

Upon receipt for Calibration, the instrument was found to be:

12/4/2019

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.

The information supplied relates to the calibrated item listed above.

West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

Approved by: Fc

Calibration Date:

19-Sep-18

Felix Christopher (QA Mgr.)

Certificate No:

29156 -2

West Caldwell

ISO/IEC 17025:2005

QA Doc. #1051 Rev. 2.0 10/1/01

Certificate Page 1 of 1

ACCREDITED

uncompromised calibration Laboratories, Inc.

1575 State Route 96, Victor, NY 14564, U.S.A.

Calibration Lab. Cert. # 1533.01

 FCC ID: A3LSMJ737P
 HAC (T-COIL) TEST REPORT
 Approved by: Quality Manager

 Filename:
 1M1910220167-01-R1.A3L
 DUT Type: Portable Handset
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REV 3.3.M 08/13/2019



1575 State Route 96, Victor NY 14564



REPORT OF CALIBRATION

TEM Consulting LP Axial T Coil Probe Company: PCTest Enginering Lab

Model No.: Axial T Coil Probe

Serial No.: TEM-1123 I. D. No.: XXXX

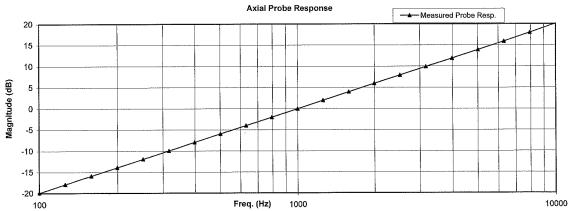
Calibration results: Probe Sensitivity measured with Helmholtz Coil Helmholtz Coll; Before & after data same: ... X ... the number of turns on each coil; 10 No. 0.204 Laboratory Environment: the radius of each coil, in meters; Ambient Temperature: °C 0.08 22.7 Α the current in the coils, in amperes.; Helmholtz Coil Constant; 7.09 A/m/V Ambient Humidity: % RH Helmholtz Coil magnetic field; 5.95 A/m Ambient Pressure: 99.326 Calibration Date: 19-Sep-2018 Calibration Due: Probe Sensitivity at 1000 Hт -59.89 dBV/A/m. Report Number: 29156 -2 was 1.013 mV/A/m Control Number: 29156 903 Ohms Probe resistance The above listed instrument meets or exceeds the tested manufacturer's specifications.

This Calibration is traceable through NIST test numbers:

683/284413-14

The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell

Calibration Laboratories Inc. procedure :

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, IŞØ)17025

Cal. Date: 19-Sep-2018

Measurements performed by:

James Zhu

Calibrated on WCCL system type 9700 This document shall not be reproduced, except in full, without the written approval from West Caldwell Cal. Labs. Inc.

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Page 1 of 2

FCC ID: A3LSMJ737P	PCTEST*	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 36 of 46
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HCATEMC_TEM-1123_Sep-19-2018

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

for

TEM Consulting LP Axial T Coil Probe Company: PCTest Enginering Lab

Model No.: Axial T Coil Probe

Serial No.: TEM-1123

Function	Tolera	nce	Measured values		
				Out	Remarks
Probe Sensitivity at	1000 Hz.	dBV/A/m	-59.89		
		dB			
Probe Level Linearity		6	6.03		
	Ref. (0 dB)	0	0.00		
		-6	-6.03		
		-12	-12.05		
	***************************************	Hz			
Probe Frequency Response					
	Ref. (0 dB)		1		
			1		
			1		
			1		
		10000	20.1		
		Probe Sensitivity at 1000 Hz. Probe Level Linearity Ref. (0 dB)	Probe Sensitivity at 1000 Hz. dBV/A/m Probe Level Linearity 6 Ref. (0 dB) 0 -6 -12 Probe Frequency Response 100 126 158 200 251 316 398 501 631 794	Probe Sensitivity at 1000 Hz. dBV/A/m -59.89 Probe Level Linearity 6 6 6.03 Ref. (0 dB) 0 0.00 -6 -6.03 -12 -12.05 Probe Frequency Response 100 -19.9 158 -15.9 200 -13.9 251 -11.9 316 -9.9 398 -7.9 501 -6.0 631 -4.0 794 -2.0 Ref. (0 dB) 1000 0.0 1259 2.0 1585 4.0 1995 5.9 2512 7.9 3162 9.9 3981 11.9 5012 13.9 6310 15.9 7943 18.0	Probe Sensitivity at 1000 Hz. dBV/A/m -59.89 Probe Level Linearity Ref. (0 dB) 0 0.00 -6 -6.03 -12 -12.05 Probe Frequency Response 100 -19.9 126 -17.9 158 -15.9 200 -13.9 251 -11.9 316 -9.9 398 -7.9 501 -6.0 631 -4.0 794 -2.0 Ref. (0 dB) 1000 0.0 1259 2.0 1585 4.0 1995 5.9 2512 7.9 3162 9.9 3981 11.9 5012 13.9 6310 15.9 7943 18.0

Instruments used for o	alibration:		Date of Cal.	Traceablity No.	Due Date
HP	34401A	S/N US360641	25-Jul-2018	,287708	25-Jul-2019
HP	34401A	S/N US361024	25-Jul-2018	,287708	25-Jul-2019
HP	33120A	S/N US360437	25-Jul-2018	,287708	25-Jul-2019
B&K	2133	S/N 1583254	25-Jul-2018	683/284413-14	25-Jul-2019

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

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Tested by: James Zhu

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCATEMC

Page 2 of 2

FCC ID: A3LSMJ737P	PCTEST SEMESTING LABORATORY, AV.	HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
Filename:	Test Dates:	DUT Type:		Page 37 of 46
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Certificate of Calibration

for

RADIAL T COIL PROBE

Manufactured by:

TEM CONSULTING LP

Model No: Serial No: RADIAL T COIL PROBE TEM-1129

Calibration Recall No:

29156

Submitted By:

Customer:

Andrew Harwell

Company: Address:

PCTest Engineering Lab 6660-B Dobbin Road

Columbia

MD 21045

The subject instrument was calibrated to the indicated specification using standards traceable to the National Institute of Standards and Technology or to accepted values of natural physical constants. This document certifies that the instrument met the following specification upon its return to the submitter.

West Caldwell Calibration Laboratories Procedure No.

RADIAL T TEM C

Upon receipt for Calibration, the instrument was found to be:

10/4/2015

Within (X)

tolerance of the indicated specification. See attached Report of Calibration.
The information supplied relates to the calibrated item listed above.
West Caldwell Calibration Laboratories' calibration control system meets the requirements, ISO 10012-1 MIL-STD-45662A, ANSI/NCSL Z540-1, IEC Guide 25, ISO 9001:2008 and ISO 17025.

Note: With this Certificate, Report of Calibration is included.

Approved by: FC

Calibration Date:

QA Doc. #1051 Rev. 2.0 10/1/01

19-Sep-18

Felix Christopher (QA Mgr.)

Certificate No:

29156 -1

Certificate Page 1 of 1

ISO/IEC 17025:2005

West Caldwell Calibration

uncompromised calibration Laboratories, Inc.

A CANTERNAL

1575 State Route 96, Victor, NY 14564, U.S.A.

ACCREDITED

Calibration Lab. Cert. # 1533.01

 FCC ID: A3LSMJ737P
 HAC (T-COIL) TEST REPORT
 Approved by: Quality Manager

 Filename:
 Test Dates:
 DUT Type:

 1M1910220167-01-R1.A3L
 10/21/2019 - 10/22/2019
 Portable Handset

HCRTEMC_TEM-1129_Sep-19-2018



1575 State Route 96, Victor NY 14564



REPORT OF CALIBRATION

TEM Consulting LP Radial T Coil Probe ,Company: PCTest Engineering Lab

Model No.: Radial T Coil Probe

Serial No.: TEM-1129

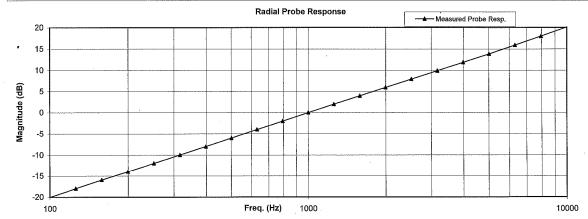
I. D. No.: XXXX

Probe Sensitivity measured wit	h Helmhol	tz Coil			
Helmholtz Coil;			Before & after data same:	X	
the number of turns on each coil;	10	No.			
the radius of each coil, in meters;	0.204	m	Laboratory Environment:		
the current in the coils, in amperes.;	0.08	Α	Ambient Temperature:	22.7	°C
Helmholtz Coil Constant;	7.09	A/m/V	Ambient Humidity:	52.1	% RH
Helmholtz Coil magnetic field;	5.95	A/m	Ambient Pressure:	99.326	kPa
			Calibration Date:	19-Sep-2018	
Probe Sensitivity at	1000	Hz.	Re-calibration Due:		
was	-60.37	dBV/A/m	Report Number:	29156	-1
	0.958	mV/A/m	Control Number:	29156	
Probe resistance	886	Ohms			

This Calibration is traceable through NIST test numbers: The expanded uncertainty of calibration: 0.30dB at 95% confidence level with a coverage factor of k=2.

683/284413-14

Graph represents Probes Frequency Response.



The above listed instrument was checked using calibration procedure documented in West Caldwell

Calibration Laboratories Inc. procedure :

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

Calibration was performed by West Caldwell Calibration Laboratories Inc. under Operating Procedures

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISQ 17025

Cal. Date: 19-Sep-2018

Measurements performed by: James Zhu

Calibrated on WCCL system type 9700

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Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

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HCRTEMC_TEM-1129_Sep-19-2018

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Victor NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Radial T Coil Probe Company: PCTest Engineering Lab

for Model No.: Radial T Coil Probe

Serial No.: TEM-1129

Function	Function Tolera			Measured values		
			Before	Out	Remarks	
Probe Sensitivity at	1000 Hz.	dBV/A/m	-60.37			
		dB				
Probe Level Linearity		6	6.03			
	Ref. (0 dB)	0	0.00			
		-6	-6.03			
		-12	-12.05			
	- Although	Hz				
Probe Frequency Response						
	Ref. (0 dB)					
			15.9			
			18.0			
		10000	20.1			
		Probe Sensitivity at 1000 Hz. Probe Level Linearity Ref. (0 dB)	Probe Sensitivity at 1000 Hz. dBV/A/m Probe Level Linearity Ref. (0 dB) Ref. (0 dB) O -6 -12 Probe Frequency Response Hz Probe Frequency Response 100 126 158 200 251 316 398 501 631 794 Ref. (0 dB) 1000 1259 1585 1995 2512 3162 3981 5012 6310 7943	Probe Sensitivity at 1000 Hz. dBV/A/m -60.37 Probe Level Linearity 6 6 6.03 Ref. (0 dB) 0 0.00 -6 -6.03 -12 -12.05 Probe Frequency Response 100 -20.0 126 -17.9 158 -15.9 200 -14.0 251 -12.0 316 -10.0 398 -8.0 501 -6.0 631 -4.0 794 -2.0 Ref. (0 dB) 1000 0.0 1259 2.0 Ref. (0 dB) 1000 0.0 1259 2.0 1585 4.0 1995 6.0 2512 7.9 3162 9.9 3981 11.9 5012 13.9 6310 15.9 7943 18.0	Probe Sensitivity at 1000 Hz. dBV/A/m -60.37 Probe Level Linearity Ref. (0 dB) R	

Instruments used for o	alibration:		Date of Cal.	Traceability No.	Due Date
' HP	34401A	S/N US360641	25-Jul-2018	,287708	25-Jul-2019
HP	34401A	S/N US361024	25-Jul-2018	,287708	25-Jul-2019
HP	33120A	S/N US360437	25-Jul-2018	.287708	25-Jul-2019
B&K	2133	S/N 1583254	25-Jul-2018	683/284413-14	25-Jul-2019

Cal. Date: 19-Sep-2018

Calibrated on WCCL system type 9700

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Tested by: James Zhu

Rev. 7.0 Jan. 24, 2014 Doc. # 1038 HCRTEMC

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11. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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